TOSHIBA CMOS DIGITAL INTEGRATED CIRCUIT SILICON MONOLITHIC

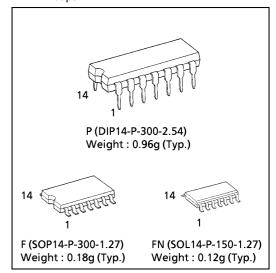
TC4030BP, TC4030BF, TC4030BFN

TC4030B QUAD EXCLUSIVE - OR GATE

TC4030B contains four circuits of exclusive OR gates. Since the buffers of two stage inverters are provided for all the outputs, the input/output voltage characteristic has been improved and the noise immunity has been also improved. And increase of transmission time due to load capacity increase is kept minimum.

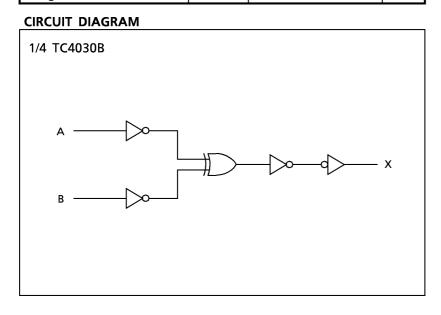
Wide variety of applications are offerred, such as digital comparators and parity circuits.

(Note) The JEDEC SOP (FN) is not available in Japan.

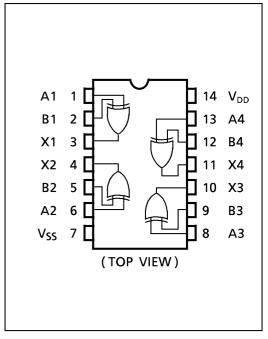


MAXIMUM RATINGS

CHARACTERISTIC	SYMBOL	RATING	UNIT
DC Supply Voltage	V_{DD}	$V_{SS} - 0.5 \sim V_{SS} + 20$	٧
Input Voltage	VIN	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	V
Output Voltage	V _{OUT}	$V_{SS} - 0.5 \sim V_{DD} + 0.5$	٧
DC Input Current	I _{IN}	± 10	mA
Power Dissipation	P _D	300 (DIP) / 180 (SOIC)	mW
Operating Temperature Range	T _{opr}	- 40~85	°C
Storage Temperature Range	T _{stg}	- 65~150	°C



PIN ASSIGNMENT



TRUTH TABLE

INOTH TABLE							
INP	OUTPUT						
Α	В	Х					
L	L	L					
L	Н	Н					
Н	L	Н					
Н	Н	L					

2001-05-17

RECOMMENDED OPERATING CONDITIONS (V_{SS} = 0V)

CHARACTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT
DC Supply Voltage	V _{DD}		3	_	18	V
Input Voltage	V _{IN}		0	_	V_{DD}	V

STATIC ELECTRICAL CHARACTERISTICS ($V_{SS} = 0V$)

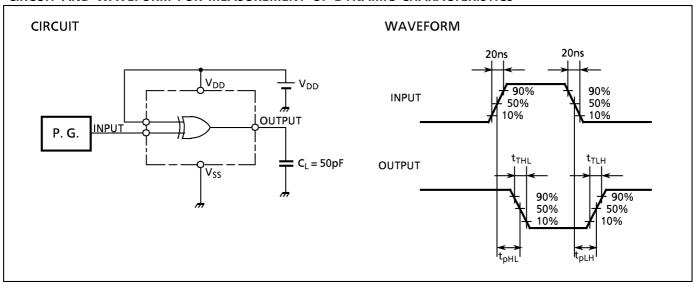
		SYM-	TEST CONDITION	V _{DD} (V)	– 40°C		25°C			85°C		UNIT
		BOL	TEST CONDITION		MIN.	MAX.	MIN.	TYP.	MAX.	MIN.	MAX.	UNIT
High-Level Output Voltage		V _{OH}	$ I_{OUT} < 1\mu A$ $V_{IN} = V_{SS}, V_{DD}$	5 10 15	4.95 9.95 14.95	111	4.95 9.95 14.95	5.00 10.00 15.00		4.95 9.95 14.95		V
Low-Level Output Voltage		$ I_{OUT} < 1\mu A$ $V_{IN} = V_{SS}, V_{DD}$	5 10 15		0.05 0.05 0.05		0.00 0.00 0.00	0.05 0.05 0.05		0.05 0.05 0.05	V	
Output H Current	ligh	I _{OH}	$V_{OH} = 4.6V$ $V_{OH} = 2.5V$ $V_{OH} = 9.5V$ $V_{OH} = 13.5V$ $V_{IN} = V_{SS}$, V_{DD}	5 5 10 15	- 0.61 - 2.50 - 1.50 - 4.00	_	- 0.51 - 2.10 - 1.30 - 3.40	- 2.2		- 0.42 - 1.70 - 1.10 - 2.80	_	mA.
Output L Current	ow	I _{OL}	$V_{OL} = 0.4V$ $V_{OL} = 0.5V$ $V_{OL} = 1.5V$ $V_{IN} = V_{SS}, V_{DD}$	5 10 15	0.61 1.50 4.00	_	0.51 1.30 3.40	1.2 3.2 12.0		0.42 1.10 2.80	_	
Input High Voltage		V _{IH}	$V_{OUT} = 0.5V, 4.5V$ $V_{OUT} = 1.0V, 9.0V$ $V_{OUT} = 1.5V, 13.5V$ $ I_{OUT} < 1\mu A$	5 10 15	3.5 7.0 11.0		3.5 7.0 11.0	2.75 5.50 8.25		3.5 7.0 11.0		V
Input Low Voltage		V _{IL}	$V_{OUT} = 0.5V, 4.5V$ $V_{OUT} = 1.0V, 9.0V$ $V_{OUT} = 1.5V, 13.5V$ $ I_{OUT} < 1\mu A$	5 10 15		1.5 3.0 4.0		2.25 4.50 6.75	1.5 3.0 4.0		1.5 3.0 4.0	V
Input	"H"Level	I _{IH}	V _{IH} = 18V	18	_	0.1	_	10 ⁻⁵	0.1	_	1.0	
Current	"L" Level	I _{IL}	$V_{IL} = 0V$	18		- 0.1	_	- 10 ⁻⁵	-0.1	_	- 1.0	
Quiescen ⁻ Current	t Supply	I _{DD}	$V_{IN} = V_{SS}, V_{DD}*$	5 10 15		1 2 4		0.001 0.001 0.002	1 2 4	_ _ _	7.5 15.0 30.0	μΑ

^{*} All valid input combinations.

DYNAMIC ELECTRICAL CHARACTERISTICS (Ta = 25° C, Vss = 0V, C_L = 50_{P} F)

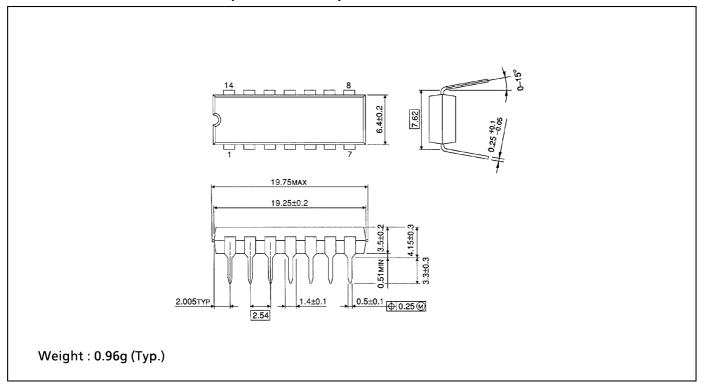
CHARACTERISTIC	SYMBOL	TEST CONDITION	V _{DD} (V)	MIN.	TYP.	MAX.	UNIT
			5	_	70	200	
Output Transition Time	t _{TLH}		10	_	35	100	
(Low to High)			15	_	30	80	
Output Transition Time (High to Low)			5	_	70	200	ns
	t_{THL}		10	_	35	100	
			15	_	30	80	
Propagation Delay Time	4		5	_	90	280	
	t _{pLH}		10	_	45	130	ns
	t _{pHL}		15	_	35	100	
Input Capacitance	C _{IN}			_	5	7.5	pF

CIRCUIT AND WAVEFORM FOR MEASUREMENT OF DYNAMIC CHARACTERISTICS



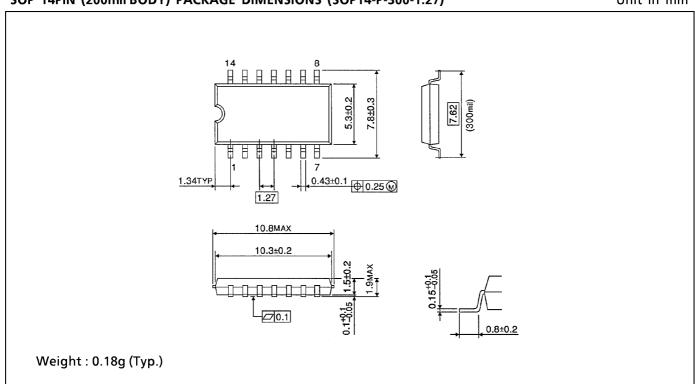
DIP 14PIN PACKAGE DIMENSIONS (DIP14-P-300-2.54)

Unit in mm



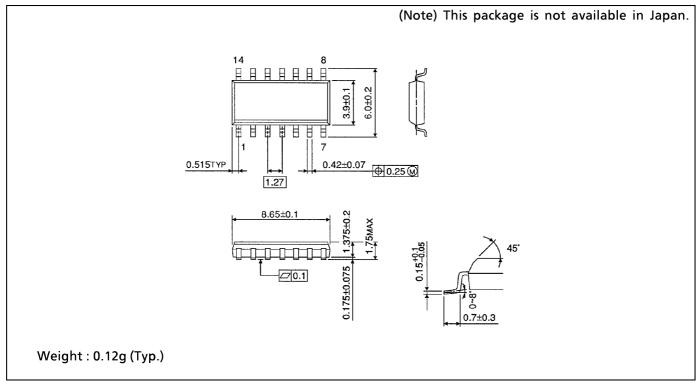
SOP 14PIN (200mil BODY) PACKAGE DIMENSIONS (SOP14-P-300-1.27)

Unit in mm



SOP 14PIN (150mil BODY) PACKAGE DIMENSIONS (SOL14-P-150 -1.27)

Unit in mm



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